

Application/Control No.	Applicant(s)/Patent under Reexamination							
10/634,229	BANSAL, JAI P.							
Examiner	Art Unit							

						Sun J. Lin 2						2825							
				15	SSU	EC	LAS	SIF	CA	TIOI	J								
OF	RIGINAL					CROSS REFERENCE(S)													
CLASS SUBCLASS CLASS						SUBCLASS (ONE SUBCLASS PER BLOCK)													
716	1	6		716		7	8	3								T			
INTERNATIONA	AL CLASSI	CATION																	
G 0 6 F		7/50																	
0 0	,																		
		1																	
		1																	
		1																	
		1																	
Jams	Bun	BD	_																
		TACY							Tota	l Clain	ıs Allo	wed:	6						
LIN, SUNJAMES (03/24/2005) (Assistant Exampiner) (Date)						RIMAI	HAE	(AMIN	ER .		1								
ALEgal Instruments Examiner) (Date)							1 A 1)	7	16	حدا		O.G.).G.		
						Primary Examiner) (Date)							Print Claim(s) Print				nt Fig		
/Legai instri	uments Ex	aminer)	/(Date	9)		(F.11)	naiy La	аншы		(Date	,			1			1		
Паг		1: 41												_					
Claims re	enumber	7 7	e sam	e orde		oresen	ted by		cant					.D.	333333333	□ R			
Final	<u>a</u>	Original		a	Original		<u>a</u>	Original		a	Original		<u>0</u>	Original		<u></u>	Original		
Final	Final	Si		Final	Orig		Final)rig		Final)rig		Final	rig		Final	rid		
																<u> </u>	Ь.		
1 1 2		31			61 62			91			121 122			151		<u> </u>	18		
2 3		33			63	1		93		,	123			152 153			18 18		
3 4		34			64	1	\vdash	94			124			154			18		
4 5		35			65			95			125			155			18		
6		36			66			96			126			156			18		
5 7	<u> </u>	37			67			97			127			157			18		
6 8	₩-	38 39			68 69			98			128			158			18		
10		40			70	ł	<u> </u>	99			129 130			159 160			18 19		
11		41			71		_	101			131			161			19		
12		42			72			102			132			162			19		
13		43			73			103			133			163			19		
14	<u> </u>	44			74			104			134			164			19		
15 16	-	45 46			75 76			105			135			165			19		
17	<u> </u>	46			77			106 107			136 137			166 167			19 19		
	 	1 10			70			107			107			107			1 19		